

BSC120N03LS G-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^{a, e}	Q _g (Typ)			
30	0.007 at V _{GS} = 10 V	80	31 nC			
30	0.009 at V _{GS} = 4.5 V	60	31110			

DFN5X6 Single Top View Bottom View

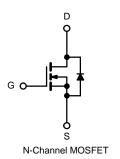
FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2011/65/EU



APPLICATIONS

- OR-ing
- Server
- DC/DC



ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)							
Parameter	Symbol	Limit		Unit			
Drain-Source Voltage		V _{DS}	30		V		
Gate-Source Voltage		V_{GS}	± 20				
	T _C = 25 °C		80		-		
Continuous Drain Current (T _J = 175 °C)	T _C = 70 °C	L	60				
Continuous Diain Current (1) = 173 C)	T _A = 25 °C	l _D	50b, c		A		
	T _A = 70 °C		45 ^{b, c}		1 ^		
Pulsed Drain Current		I _{DM}	210				
Avalanche Current Pulse	$L = 0.1 \text{ mH} \qquad \frac{I_{AS}}{E_{AS}}$	60					
Single Pulse Avalanche Energy		E _{AS}	95		mJ		
Continuous Source-Drain Diode Current	T _C = 25 °C	l _s	80 60		Α		
Continuous Source-Drain Diode Current	T _A = 25 °C	'S			1 ^		
Maximum Power Dissipation	T _C = 25 °C	В	155		W		
Waximum Tower Dissipation	T _C = 70 °C	P _D	105				
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175		°C		
THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Тур.	Max.	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 sec	R_{thJA}	32	40	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	C/VV		

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C
V _{GS(th)} Temperature Coefficient	e Coefficient $\Delta V_{GS(th)}/T_J$			- 7.5		1117/
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	0.5		2.0	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
Zero Gate Voltage Brain Gunerit	טטי	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μΛ
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 30.8 \text{ A}$		0.007		Ω
Dialii-Source Oii-State Resistance	'`DS(on)	$V_{GS} = 4.5 \text{ V}, I_D = 27 \text{ A}$		0.009		22
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_{D} = 30.8 \text{ A}$		160		S
Dynamic ^b						
Input Capacitance	C_{iss}					
Output Capacitance	C_{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$			425	pF
Reverse Transfer Capacitance	C_{rss}				170	
Total Gate Charge	Q_{g}	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 30.8 \text{ A}$			61	
Total Gate Griange	•				31.5	nC
Gate-Source Charge	Q_gs	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 27.8 \text{ A}$		10		0
Gate-Drain Charge	Q_gd				6	
Gate Resistance	R_g	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	$t_{d(on)}$			18	27	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		11	17	
Turn-Off Delay Time	$t_{d(off)}$	$I_D \cong 24 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		70	105	
Fall Time	t_f			10	15	ns
Turn-On Delay Time	$t_{d(on)}$			55	83	110
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.67 Ω		180	270	
Turn-Off Delay Time	$t_{d(off)}$	$I_D \cong 22.5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		55	83	
Fall Time	t _f			12	18	

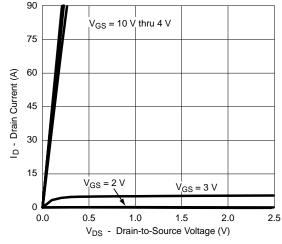
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

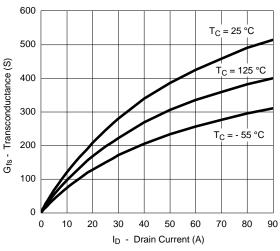
a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$ b. Guaranteed by design, not subject to production testing.



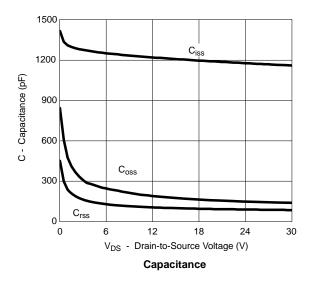
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







Transconductance



3.0

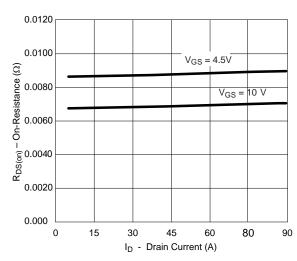
2.4

($\underbrace{\mathsf{C}}_{\mathsf{T}}$)

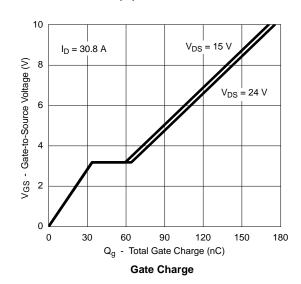
1.8 $\mathsf{T}_{\mathsf{C}} = 25\,^{\circ}\mathsf{C}$ $\mathsf{T}_{\mathsf{C}} = 125\,^{\circ}\mathsf{C}$ 0.0

1 2 3 4 V_{GS} - Gate-to-Source Voltage (V)

Transfer Characteristics



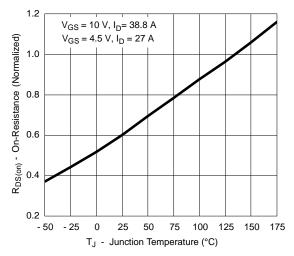
R_{DS(on)} vs. Drain Current



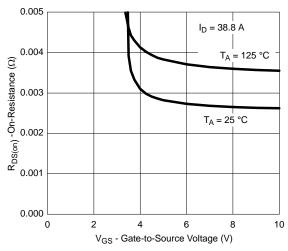
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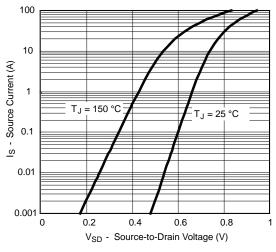
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



On-Resistance vs. Junction Temperature



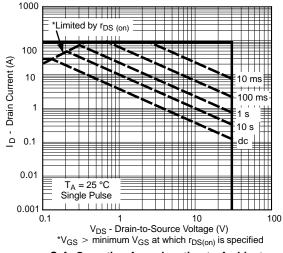
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



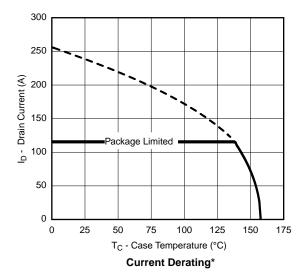
Threshold Voltage

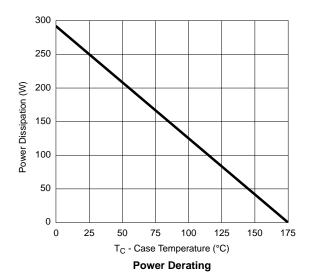


Safe Operating Area, Junction-to-Ambient

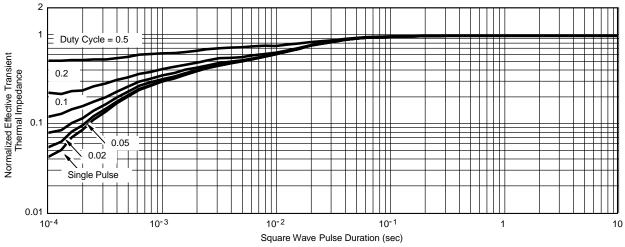


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





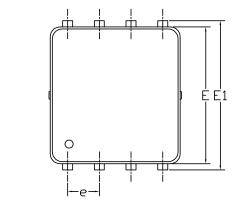
*The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

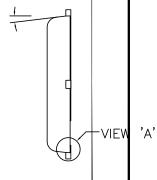


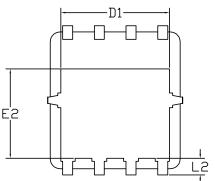
Normalized Thermal Transient Impedance, Junction-to-Case

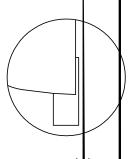
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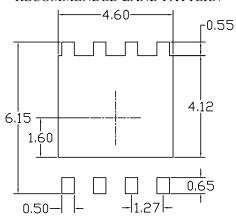






<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN



				DIM	7	
				MIN	NOM	MAX
	0.85		1.00	0.033	0.037	0.039
	0.00		0.05	0.000		0.002
	0.30		0.50	0.0/12		0.020
c	0.15	0. 20	0.25	0,/006	0.008	0.010
				/	0.20	
D1		4. 35			0. 171	
		5. 55			0.219	
		6.05			0. 238	
E2		3. 625			0.143	
e		1.27 BSC			0.050 BSC	•
L	0.45	0. 55	0.65	0.018	0.022	0.026
L1	0		0.15	0		0.006
L2		0.68 REF			0.027 REF	
	0°		10°	0°		10°

NOTE

UNIT: mm

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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